

N-Channel MOSFET

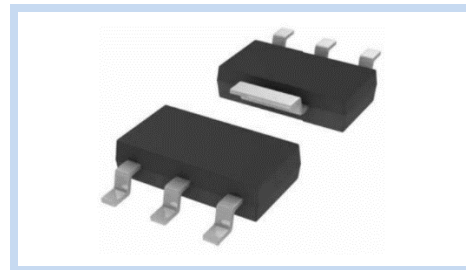
60V 4A 3W SOT-223

MFT6N4A0S223

MERITEK

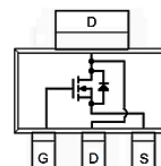
FEATURE

- $R_{DS(ON)} < 102m\Omega$, $V_{GS}=10V$, $I_D=2A$
- $R_{DS(ON)} < 126m\Omega$, $V_{GS}=4.5V$, $I_D=1A$
- High Dense Cell Design for Extremely Low $R_{DS(ON)}$.
- Application: Power Management in Note book, Battery Powered System
- Rugged Construction Design



MECHANICAL DATA

- Case: SOT-223 Package
- Terminals: Solderable per MIL-STD-750, Method 2026

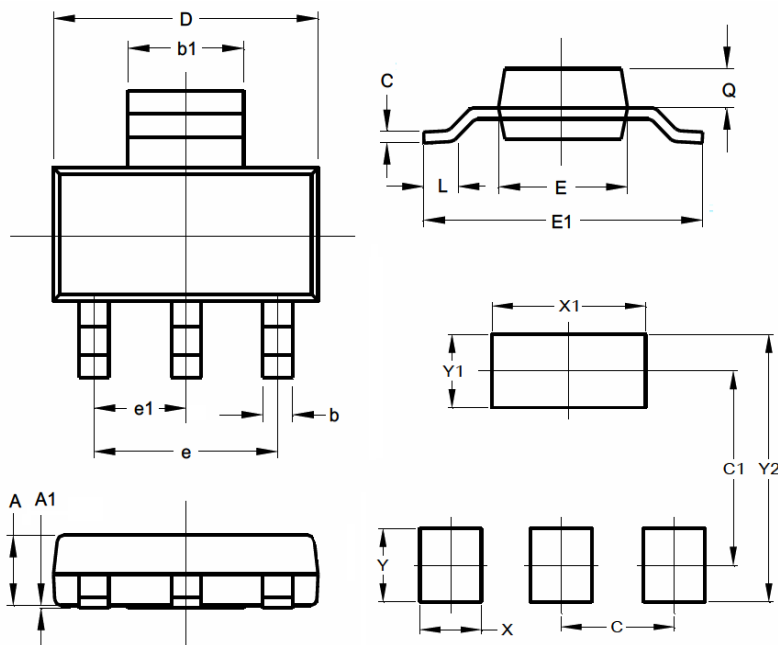


MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current – Continuous	I_D	4	A
Drain Current – Pulsed	I_{DM}	16	A
Power Dissipation	P_D	3	W
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 150	$^{\circ}C$
Thermal Resistance from Junction to Ambient	$R_{\theta JA}$	42	$^{\circ}C/W$

DIMENSIONS

Item	Min (mm)	Max (mm)
A	1.50	1.70
A1	0.02	0.10
b	0.67	0.80
b1	2.95	3.20
C	0.24	0.35
D	6.30	6.85
e	4.60	
e1	2.30	
E	3.30	3.80
E1	6.70	7.30
L	0.90	--
X	1.20	
X1	3.50	
Y	1.60	
Y1	1.80	
Y2	8.00	
c	2.30	
c1	6.30	



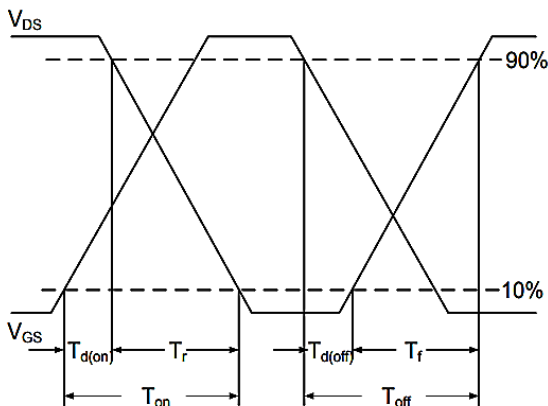
ELECTRICAL CHARACTERISTICS

Off Characteristics	Conditions	Symbol	Min	Typ.	Max	Unit
Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	BV_{DSS}	60	--	--	V
Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	$V_{GS(th)}$	1	--	3	V
Gate Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$	I_{GSS}	--	--	± 0.1	μA
Zero Gate Voltage Drain Current	$V_{DS}=60V, V_{GS}=0V$	I_{DSS}	--	--	1.0	μA
On Characteristics	Conditions	Symbol	Min	Typ.	Max	Unit
Static Drain-Source On-Resistance	$V_{GS}=10V, I_D=A$	$R_{DS(on)}$	--	85	102	m Ω
	$V_{GS}=4.5V, I_D=1A$		--	97	126	m Ω
Dynamic Characteristics	Conditions	Symbol	--	Typ.	Max	Unit
Input Capacitance	$V_{DS}=30V, V_{GS}=0V$ $F=1.0MHz$	C_{iss}	--	405	--	pF
Output Capacitance		C_{oss}	--	70	--	pF
Reverse Transfer Capacitance		C_{rss}	--	30	--	pF
Turn-On Delay Time		$T_{d(on)}$	--	7	--	nS
Rise Time	$V_{DS}=30V, I_D=-1.5A,$ $V_{GS}=10V, R_G=3\Omega$	T_r	--	2.7	--	nS
Turn-Off Delay Time		$T_{d(off)}$	--	18.8	--	nS
Fall Time		T_f	--	1.6	--	nS
Total Gate Charge	$V_{DS}=30V, V_{GS}=4.5V, I_D=-2.5A$	Q_g	--	3.6	--	nC
Gate-Source Charge		Q_{gs}	--	0.8	--	nC
Gate-Drain Charge		Q_{gd}	--	1.6	--	nC
Drain-Source Body Diode	Conditions	Symbol	Min	Typ.	Max	Unit
Diode Forward Voltage	$I_S=-1A, V_{GS}=0V$	V_{SD}	--	--	1.2	V
Diode Forward Current	--	I_S	--	--	2.5	A

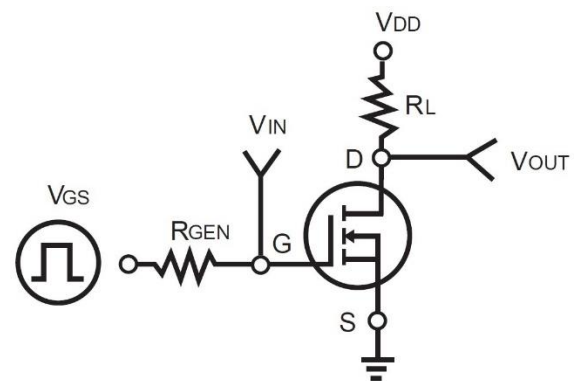
Note:

1. $T_A = 25^\circ C$ unless otherwise noted.
2. Pulse test: Pulse width < 300 μs , Duty cycle < 2%.
3. Repetitive Rating: Pulse width limited by maximum junction temperature
4. Device mounted on FR-4 Board, $t \leq 10$ sec.
5. Guaranteed by design, not subject to production testing.

Switching Time Waveform

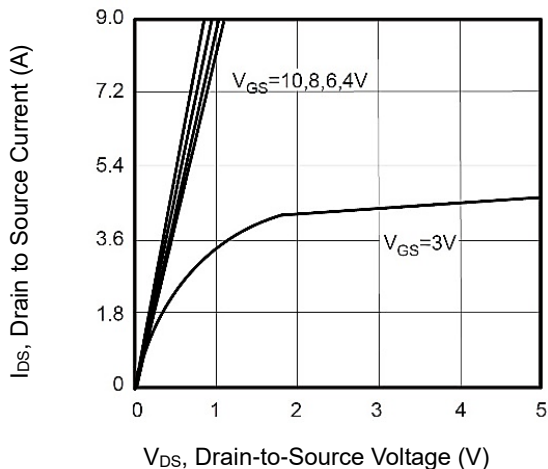


Switching Test Circuit

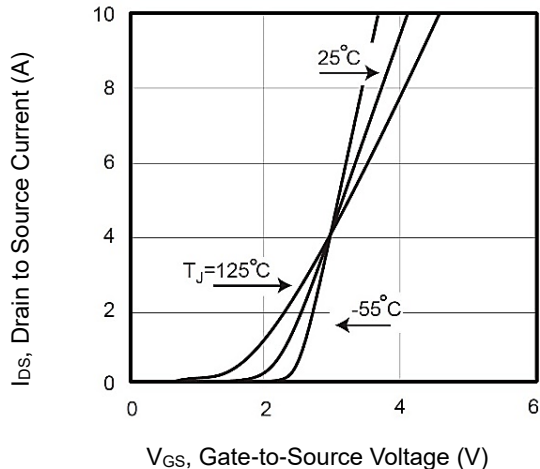


CHARACTERISTIC CURVES

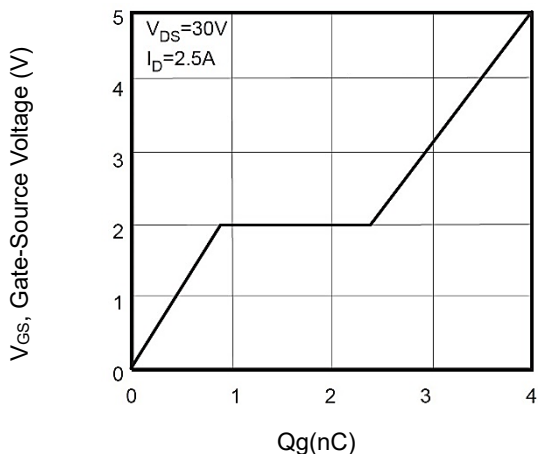
On Region Characteristics



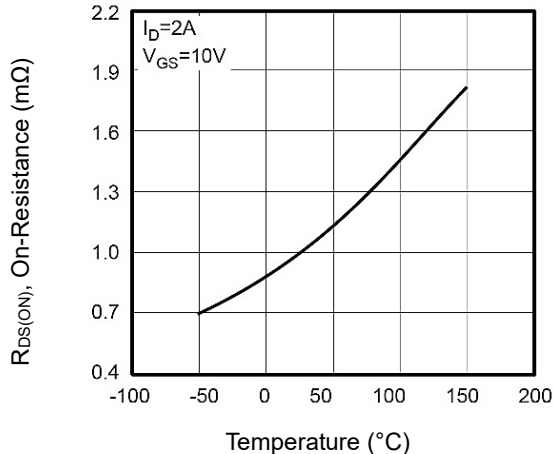
Transfer Characteristics



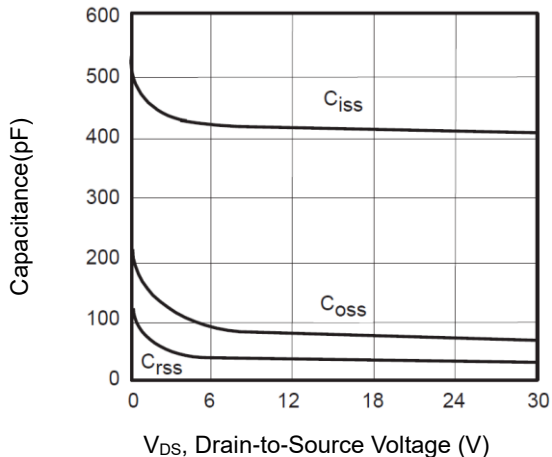
Gate Charge Characteristics



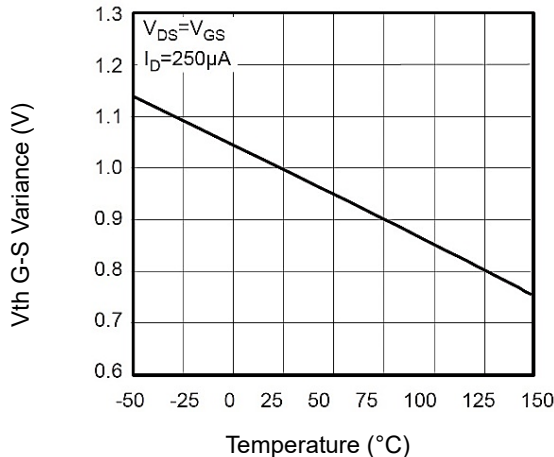
On-Resistance vs. Junction Temperature



Capacitance vs. Drain-Source Voltage

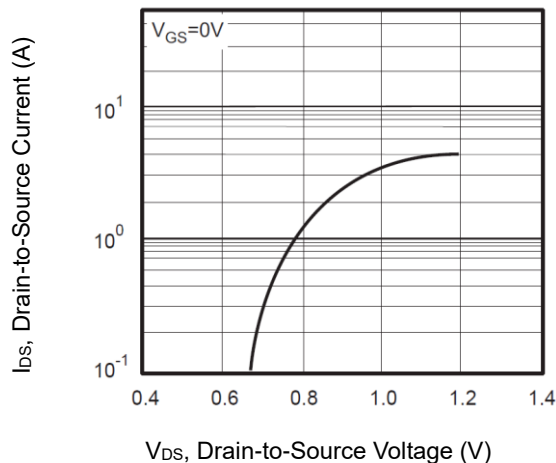


Threshold Voltage Variance vs. Temperature

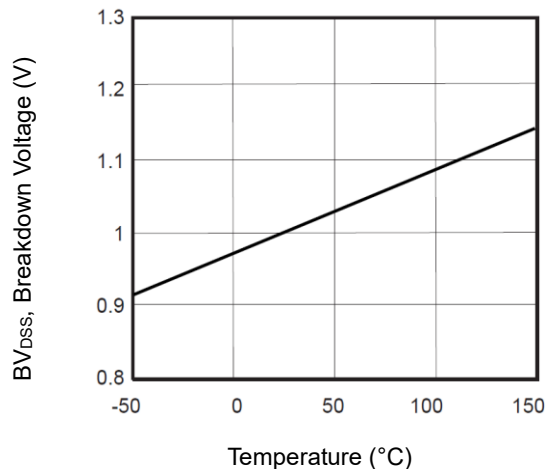


CHARACTERISTIC CURVES

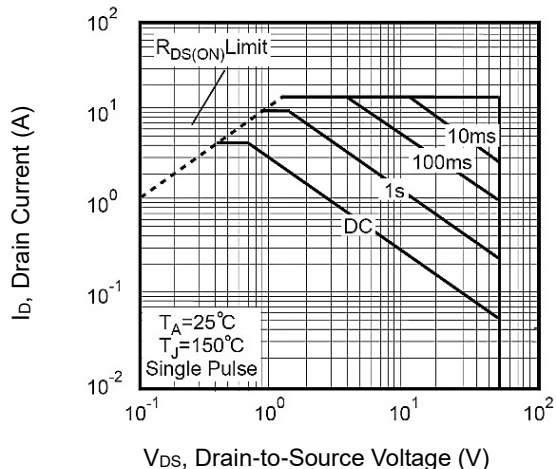
Body Diode Characteristics



Breakdown Voltage vs Temperature



Maximum Safe Operating Area



Normalized Transient Thermal Impedance vs Pulse Width

